

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LIAU, CHEE HONG	
		Examiner Saif A. Alhija	Art Unit 2128	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	D	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	"Evolving Artificial Neural Networks", Xin Yao. IEEE 1999.
	V	West, "Next Generation Test Generator (NGTG) Interface to Automatic Test Equipment (ATE) for Digital Circuits", 1997 IEEE
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.